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IR-2132 (2-3575)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

New York, New York

Thomas J. Ribarich

Date: October 29, 2004

Serial No.: 10/615,710

Group Art Unit: 2821

Filed: July 8, 2003

Examiner: Ephrem Alemu

For: CHIP BALLAST CONTROL WITH POWER FACTOR CORRECTION

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

SUBMISSION

Sir:

Submitted herewith is a copy of a search report issued by a patent searching authority other than the PTO and the cited art together with a form listing the same for the convenience of the Examiner.

I certify that each item of information contained in this Submission was cited in a communication from a foreign patent office in a counterpart foreign application and that this communication was not received by any individual designated in 37 C.F.R. 1.56(c) more than 30 days prior to the filing of this Submission.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents P.O. Box 1450, Alexandria, VA 22313-1450, on October 29, 2004

Respectfully submitted,

Brendan J. Kennedy

Name of applicant, assignee or  
Registered Representative

Signature  
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Date of Signature

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Enclosures

<b>APPLICANT'S ART CITATION</b> (Use several sheets if necessary)		Application <b>10/615,710</b>		OFGS File No. <b>IR-2132 (2-3575)</b>	
		Applicant <b>Thomas Ribarich</b>			
		Filing Date <b>July 8, 2003</b>		Group Art Unit <b>2821</b>	

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 PATENT & TRADEMARK OFFICE

U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
	US-6,211,623	04-2001	WILHELM ET AL.			
	US-					
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		

Examiner	Date Considered
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.